

Search Notes



Application/Control No.

10/721,490

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

SCHOLZ, FRANK MICHAEL

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	4/06	DN
	8		
	9		
	10		
	35		
	39		
379	45		
	42		
	90.01		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I. US	4/06	DN
1. US		
2. PG Pub		
II. FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
III. NPL		
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